Unit: mm

TOSHIBA Field Effect Transistor Silicon N-Channel MOS Type ( $\pi$ -MOSVI)

# 2SK3934

### **Switching Regulator Applications**

Low drain-source ON resistance: RDS (ON) =  $0.23\Omega$  (typ.)

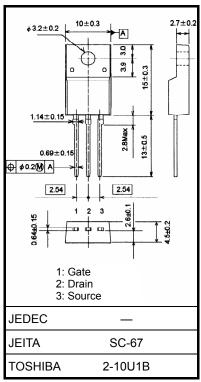
• High forward transfer admittance:  $|Y_{fs}| = 8.2 \text{ S (typ.)}$ 

• Low leakage current:  $I_{DSS} = 100 \mu A (V_{DS} = 500 V)$ 

• Enhancement model:  $V_{th} = 2.0 \sim 4.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$ 

#### **Absolute Maximum Ratings (Ta = 25°C)**

Characte	eristic	Symbol	Rating	Unit	
Drain-source voltage		$V_{DSS}$	500	V	
Drain-gate voltage (F	$R_{GS} = 20 \text{ k}\Omega$ )	$V_{DGR}$	500	V	
Gate-source voltage		$V_{GSS}$	±30	V	
	DC (Note 1)	ΙD	15		
Drain current	Pulse (t = 1 ms) (Note 1)	I <sub>DP</sub>	60	Α	
Drain power dissipati	on (Tc = 25°C)	P <sub>D</sub>	50	W	
Single pulse avalance	he energy (Note 2)	E <sub>AS</sub>	1.08	J	
Avalanche current		I <sub>AR</sub>	15	Α	
Repetitive avalanche	energy (Note 3)	E <sub>AR</sub>	5.0	mJ	
Channel temperature	;	T <sub>ch</sub>	150	°C	
Storage temperature range		T <sub>stg</sub>	-55~150	°C	



Weight: 1.7 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### **Thermal Characteristics**

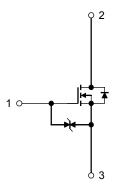
Characteristic	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	2.5	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	62.5	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C during use of the device.

Note 2:  $V_{DD} = 90 \text{ V}$ ,  $T_{ch} = 25^{\circ}\text{C}$  (initial), L = 8.16mH,  $I_{AR} = 15 \text{ A}$ ,  $R_G = 25 \Omega$ 

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Handle with care.





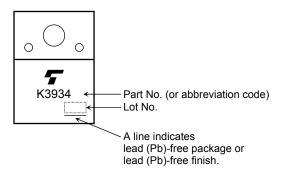
## Electrical Characteristics (Ta = 25°C)

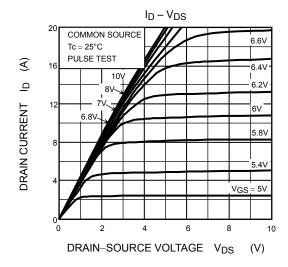
Cha	racteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cui	rrent	I <sub>GSS</sub>	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μΑ
Gate-source brea	te-source breakdown voltage V (		$I_G = \pm 10 \ \mu A, \ V_{DS} = 0 \ V$	±30	_	_	V
Drain cutoff curre	ent	I <sub>DSS</sub>	V <sub>DS</sub> = 500 V, V <sub>GS</sub> = 0 V	100		100	μА
Drain-source bre	akdown voltage	V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	500	_	_	V
Gate threshold v	oltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	2.0	_	4.0	V
Drain-source ON	resistance	R <sub>DS</sub> (ON)	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 7.5 A	_	0.23	0.3	Ω
Forward transfer	admittance	Y <sub>fS</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 7.5 A	2.3	8.2	_	S
Input capacitance	e	C <sub>iss</sub>		_	3100	_	
Reverse transfer capacitance		C <sub>rss</sub>	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	20	_	pF
Output capacitance		Coss		_	270	_	
Switching time	Rise time	t <sub>r</sub>	$V_{GS} = 7.5 \text{ A}  V_{OUT}$ $V_{GS} = 26\Omega$ $V_{DD} \approx 200 \text{ V}$ $V_{DD} \approx 200 \text{ V}$ $V_{DD} \approx 1\%, t_{W} = 10  \mu\text{s}$	_	70	_	
	Turn-on time	t <sub>on</sub>			130		ns
	Fall time	t <sub>f</sub>			70		
	Turn-off time	t <sub>off</sub>		_	280	_	
Total gate charge		Qg		_	62		
Gate-source charge		Q <sub>gs</sub>	$V_{DD} \simeq 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 15 \text{ A}$	_	40	_	nC
Gate-drain charge		Q <sub>gd</sub>		_	22	_	

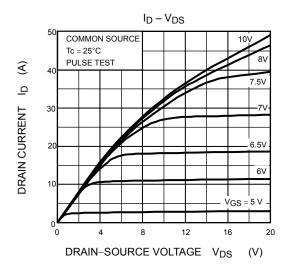
## Source-Drain Ratings and Characteristics (Ta = 25°C)

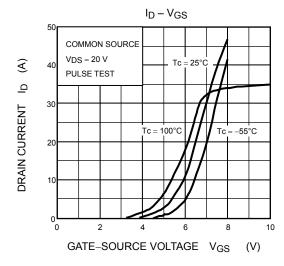
Characteristic		Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current	(Note 1)	I <sub>DR</sub>	_		_	15	Α
Pulse drain reverse current	(Note 1)	I <sub>DRP</sub>	_	_	_	60	Α
Forward voltage (diode)		$V_{DSF}$	I <sub>DR</sub> = 15 A, V <sub>GS</sub> = 0 V		_	-1.7	V
Reverse recovery time		t <sub>rr</sub>	$I_{DR} = 15 \text{ A}, V_{GS} = 0 \text{ V},$		1.3	_	μS
Reverse recovery charge		Q <sub>rr</sub>	dl <sub>DR</sub> /dt = 100 A/μs	_	18	_	μС

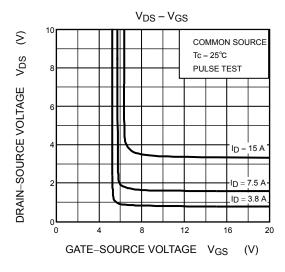
### Marking

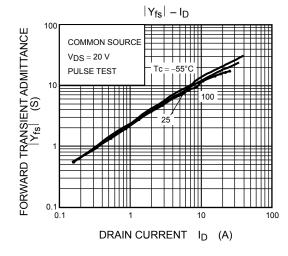


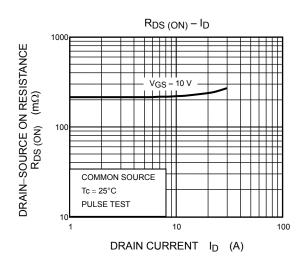


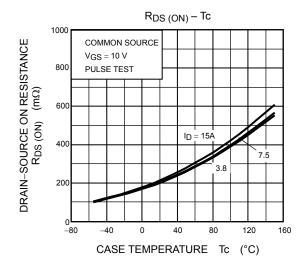


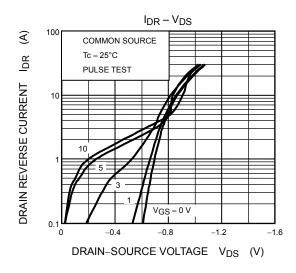


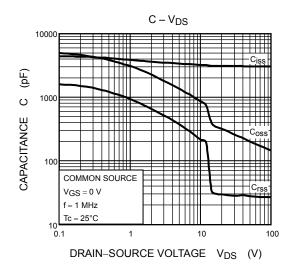


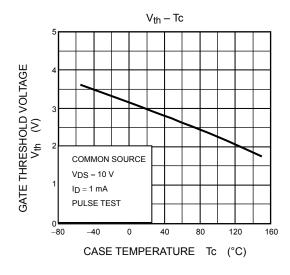


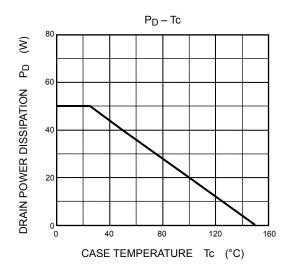


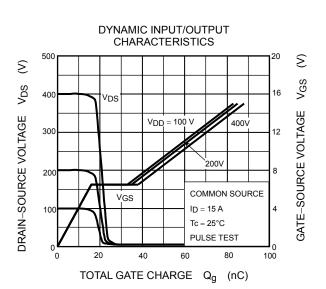


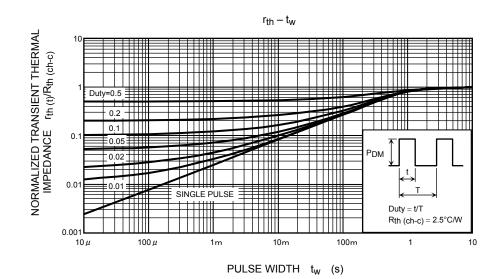


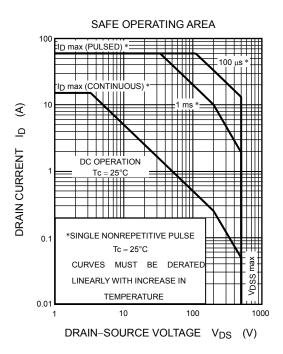


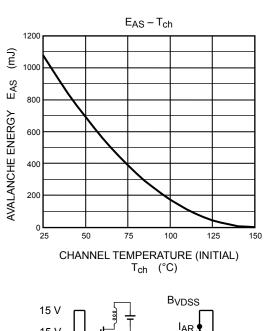


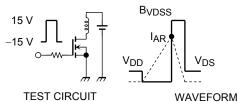












$$\begin{aligned} &R_G = 25~\Omega \\ &V_{DD} = 90~V,~L = 8.13~mH \end{aligned} \qquad EAS = \frac{1}{2} \cdot L \cdot I^2 \cdot \left( \frac{BVDSS}{BVDSS - V_{DD}} \right) \end{aligned}$$

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